

# Supplementary information

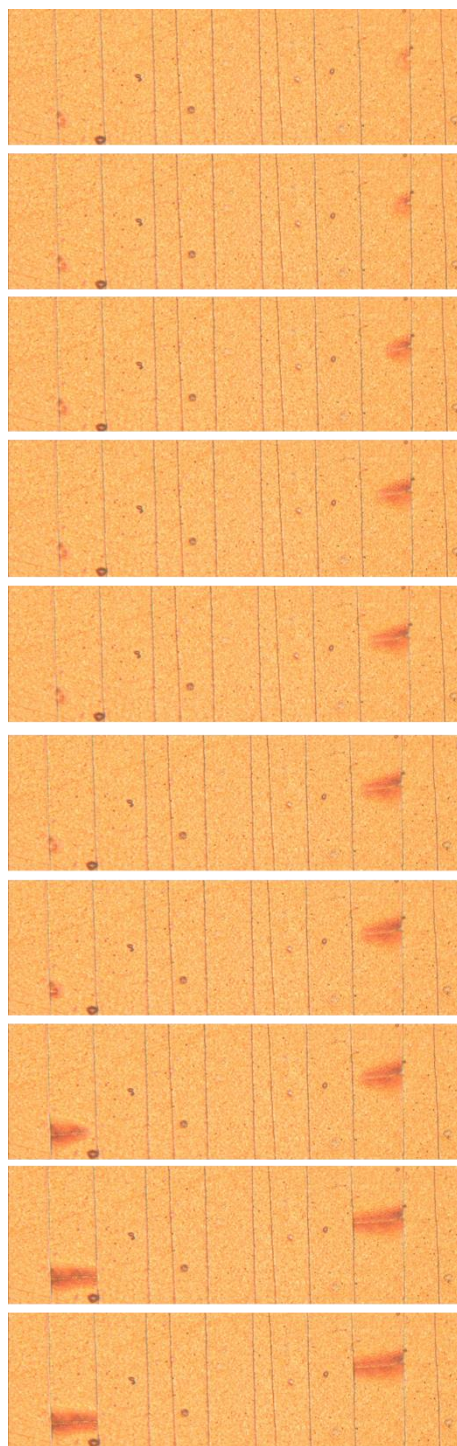
## Mechanics of Nanoscale $\varepsilon$ -Fe<sub>2</sub>O<sub>3</sub>/Organic Superlattices Towards Flexible Thin-Film Magnets

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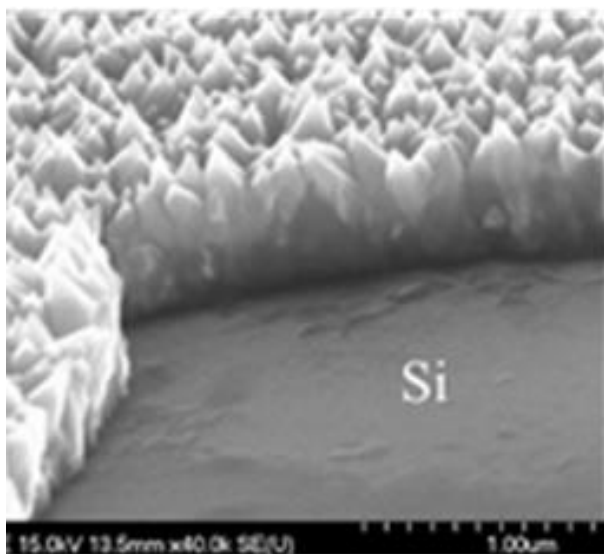
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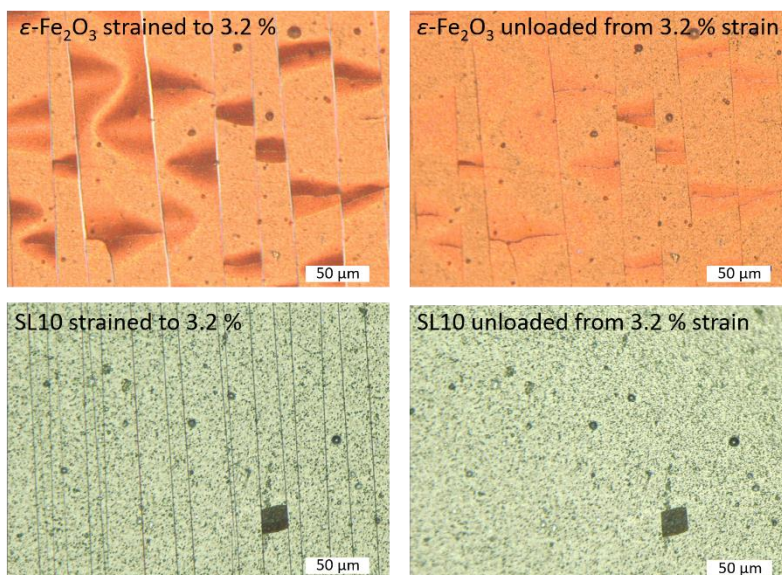
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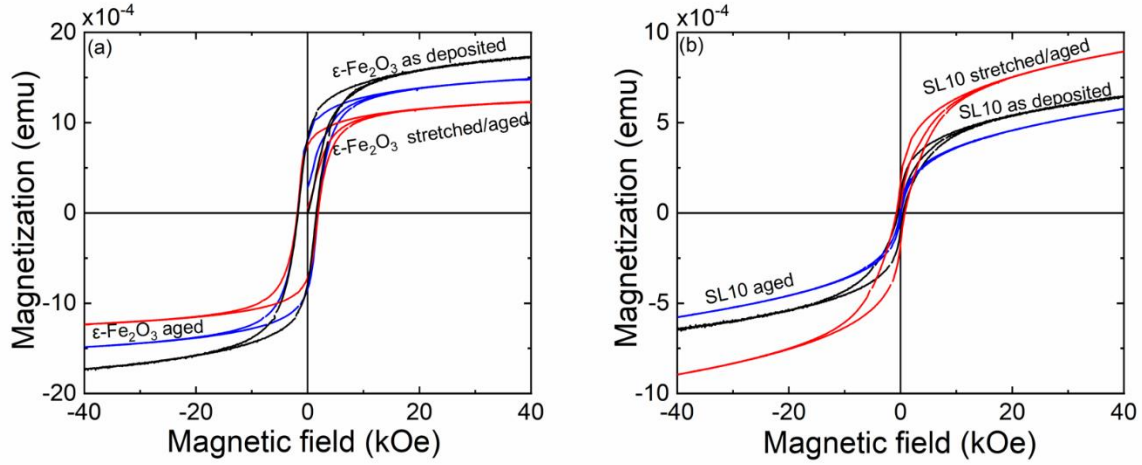
**Figure S1.** Optical micrographs for the  $\epsilon$ -Fe<sub>2</sub>O<sub>3</sub> film showing formation of two buckles. Evolution of the buckle from the triangular (top-view) shape into rectangular shape is depicted. Transverse cracks are seen to form at the apex of buckles along their shape evolution. The series begins from 2.2% tensile strain and spans over 0.14% strain interval (or 10s time interval). Width of each image is 300  $\mu$ m.



**Figure S2.** A tilted scanning-electron-microscope cross-section view of the  $\epsilon$ -Fe<sub>2</sub>O<sub>3</sub> film on Si substrate.



**Figure S3.** Optical top-view micrographs of the  $\epsilon$ -Fe<sub>2</sub>O<sub>3</sub> and SL10 film on the polyimide substrate after loading to 3.2 % tensile strain, and after subsequent unloading. Width of each image is 300  $\mu$ m.



**Figure S4.** Magnetization vs. magnetic field curves for (a) the  $\epsilon$ -Fe<sub>2</sub>O<sub>3</sub> and (b) SL10 films. The data is shown for the as-deposited films and for the films after loading to 3.2 % tensile strain, followed by subsequent unloading. As the strained samples had undergone  $\sim 1$  year storage in glovebox prior to the experiment, an additional reference measurement was done for unstrained samples with the same storage history ("aged").

**Table S1.** Fracture properties for the thin films: critical bending radius ( $R_c$ ) on 50- $\mu$ m thick polyimide, crack onset strain (COS), elastic modulus ( $E$ ), cohesive strain ( $\epsilon_{coh}$ ), and cohesive strength ( $\sigma_{coh}$ ). The error bars represent the standard deviation over 3-5 measurements. The data is shown for values without thickness normalization.

Sample	$R_c$ (mm)	COS (%)	$E$ (GPa)	$\alpha$	$\beta$	$\epsilon_{coh}$ (%)	$\sigma_{coh}$ (MPa)
$\epsilon$ -Fe <sub>2</sub> O <sub>3</sub>	7.5 $\pm$ 0.3	0.34 $\pm$ 0.02	152 $\pm$ 33	2.8 $\pm$ 0.4	0.027 $\pm$ 0.008	0.58 $\pm$ 0.09	885 $\pm$ 126
SL1	5.3 $\pm$ 0.2	0.48 $\pm$ 0.02	145 $\pm$ 37	5.0 $\pm$ 1.1	0.015 $\pm$ 0.004	0.66 $\pm$ 0.06	948 $\pm$ 80
SL10	2.9 $\pm$ 0.4	0.88 $\pm$ 0.10	70 $\pm$ 20	6.8 $\pm$ 1.7	0.021 $\pm$ 0.003	1.18 $\pm$ 0.07	824 $\pm$ 48
Fe-TP	1.9 $\pm$ 0.2	1.30 $\pm$ 0.11	32 $\pm$ 8	39 $\pm$ 16	0.015 $\pm$ 0.002	$\geq$ 1.45 $\pm$ 0.12	$\geq$ 462 $\pm$ 37

**Table S2.** Interfacial properties for the film/substrate systems (polyimide substrate): saturation crack density ( $CD_s$ ), saturation crack spacing ( $L_s$ ), interfacial shear strain ( $\varepsilon_i$ ), and interfacial shear strength ( $\sigma_i$ ). The error bars represent the standard deviation over 3-5 measurements. The data is shown for values without thickness normalization.

Sample	$CD_s$ (mm <sup>-1</sup> )	$L_s$ (μm)	$\varepsilon_i$ (%)	$\sigma_i$ (MPa)
ε-Fe <sub>2</sub> O <sub>3</sub>	34±4	30±4	0.011±0.003	17±4
SL1	39±9	27±8	0.016±0.005	23±7
SL10	54±7	19±2	0.057±0.007	40±5
Fe-TP	≥414±12	≤2.4±0.07	≥0.21±0.012	≥ 67±4